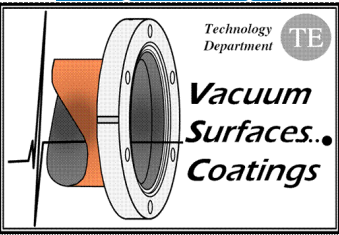




Surface Properties of LHC Vacuum Chambers

V. Baglin

CERN TE-VSC, Geneva



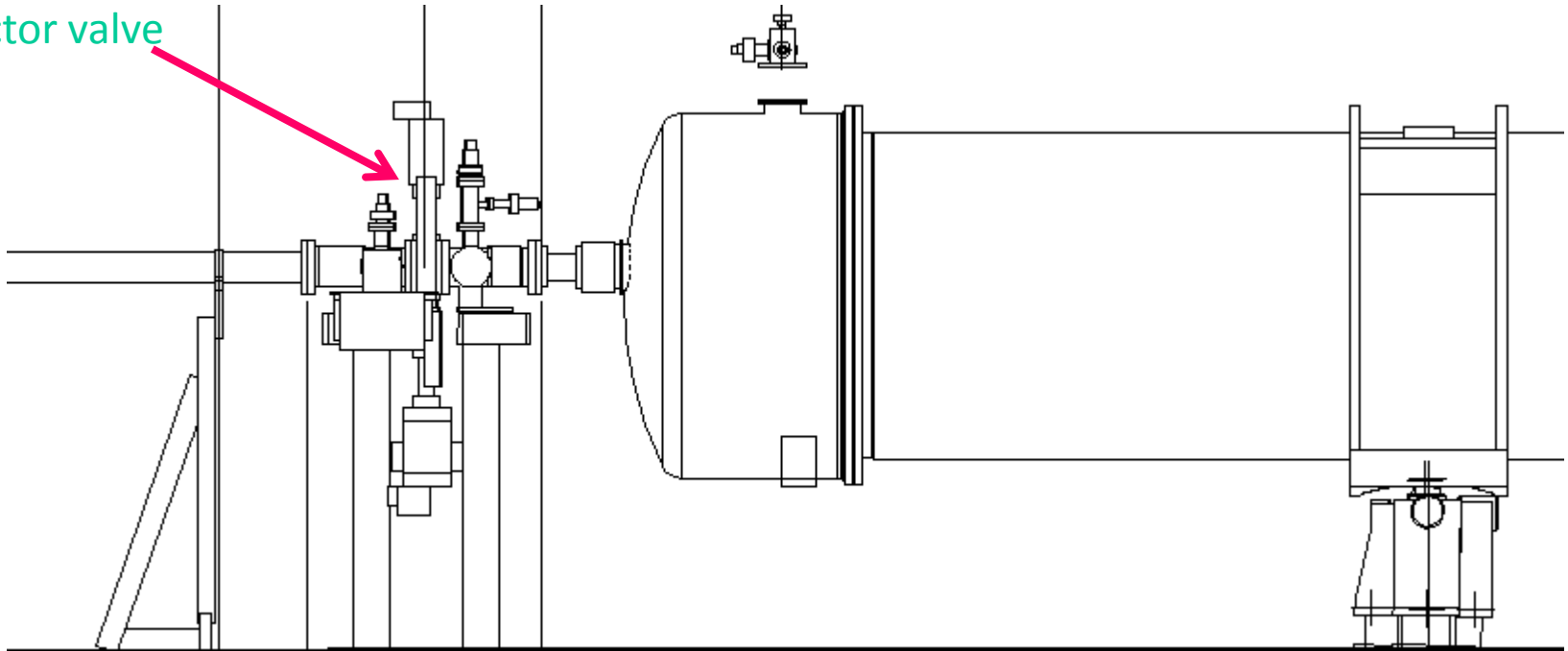
1. Vacuum chambers types in LHC
2. Electron related surface properties
3. Photon related surface properties

1. Vacuum Chamber Types in LHC

Cryogenic temperature areas : what's this ?

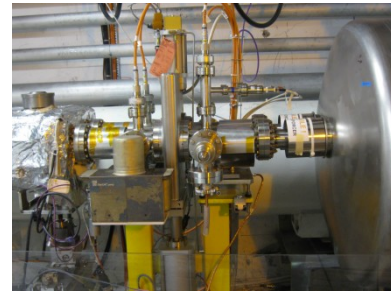
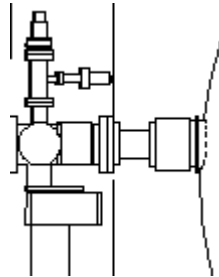
- LHC arcs,
- Stand Alone Magnets : triplets, quadrupoles, D1, D2
- At each extremity of EACH cryostat, a vacuum sector valve is installed.
- It defines a so called “cryogenic vacuum” sector
- By definition, a cryogenic vacuum sector is unbaked.

Sector valve

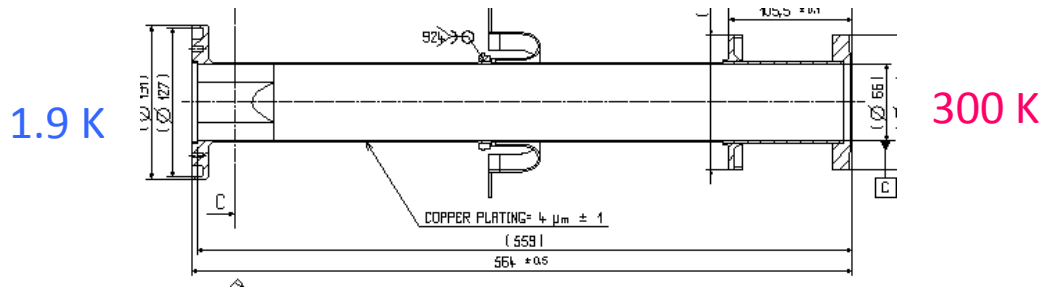


Cryogenic temperature areas : what's there ?

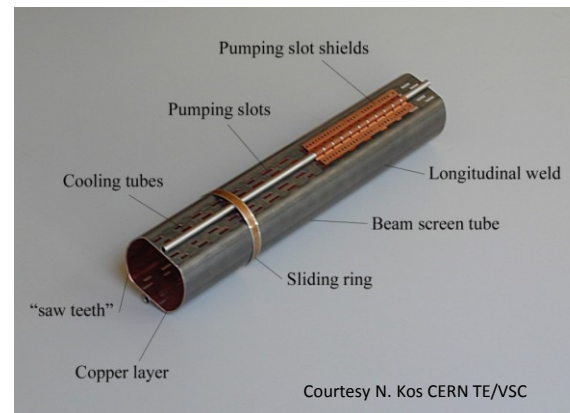
- Unbaked copper chambers operating at room temperature



- Unbaked copper plated cold warm transitions from RT to 1.9 K



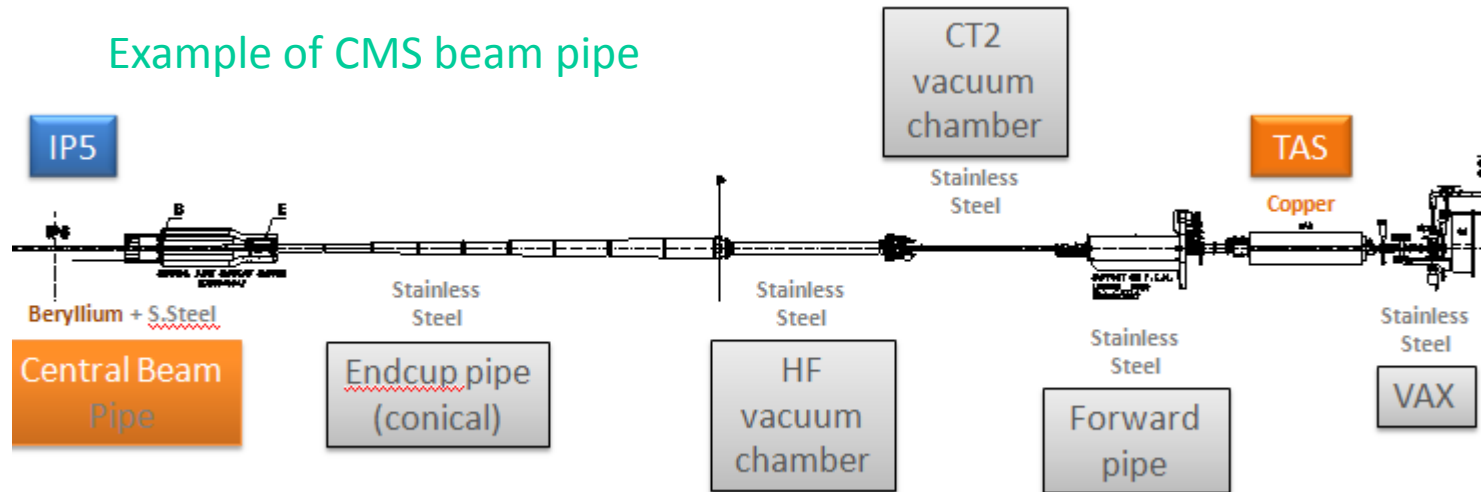
- Unbaked beam screens operating at 5-20 K



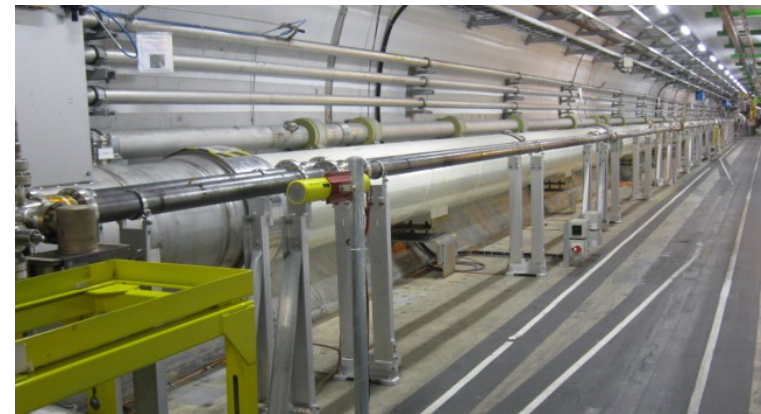
Room temperature areas : what's this ?

- LHC experiments : ATLAS, CMS, ALICE, LHC-B

Example of CMS beam pipe



- Room temperature vacuum system between sector valves

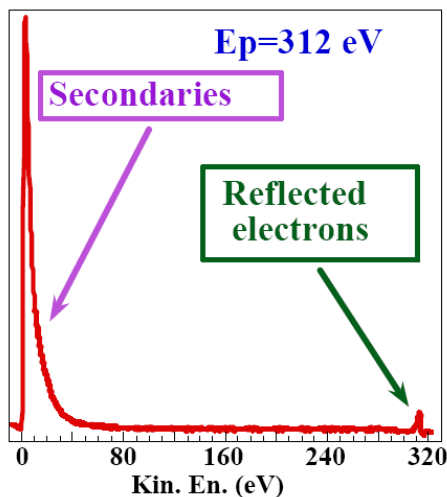


2. Electrons related surface properties

Secondary electrons curve

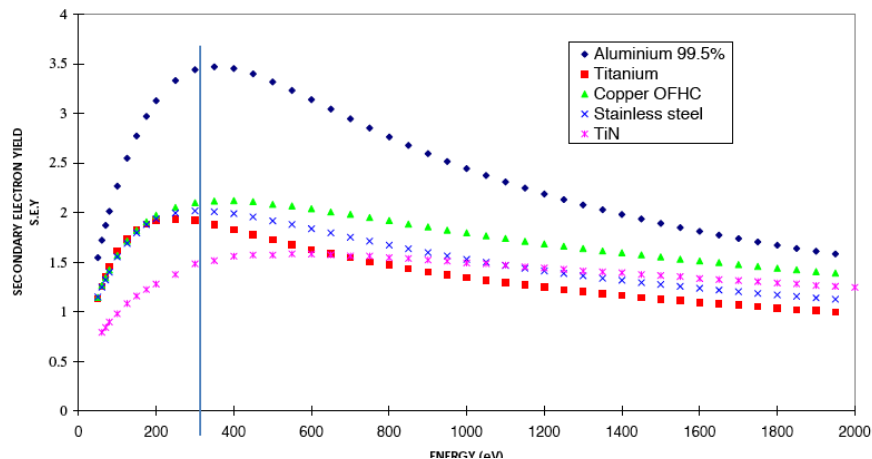
$$\delta = \frac{\text{number of produced electrons}}{\text{incident electrons}}$$

- Technical material
- Maximum around 200-300 eV
- $\delta_{\max} \sim 2$ to 3.5



R. Cimino, I.R. Collins, *App. Surf. Sci.* 235, 231-235, (2004)

“as received”



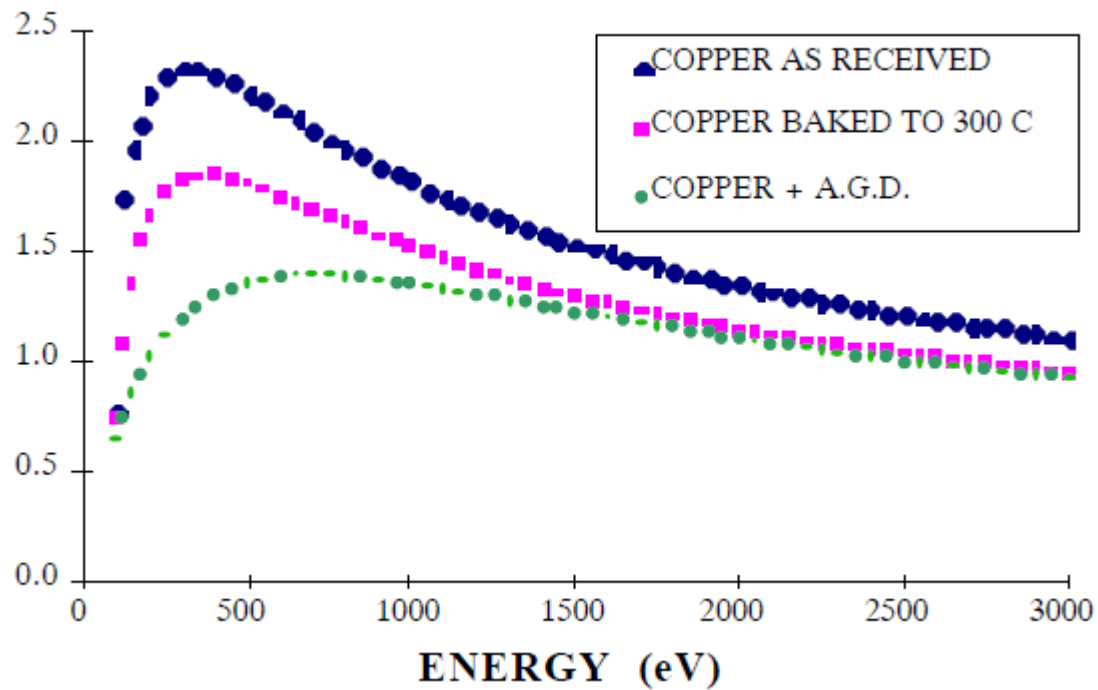
312 eV

N. Hilleret *et al.*, LHC Project Report 433 2000, EPAC 00

- The electron distribution curve (EDC) shows :
 - Component at reflected electron energy
 - Secondary electrons with low energy

Most of the emitted electrons have **low energy**

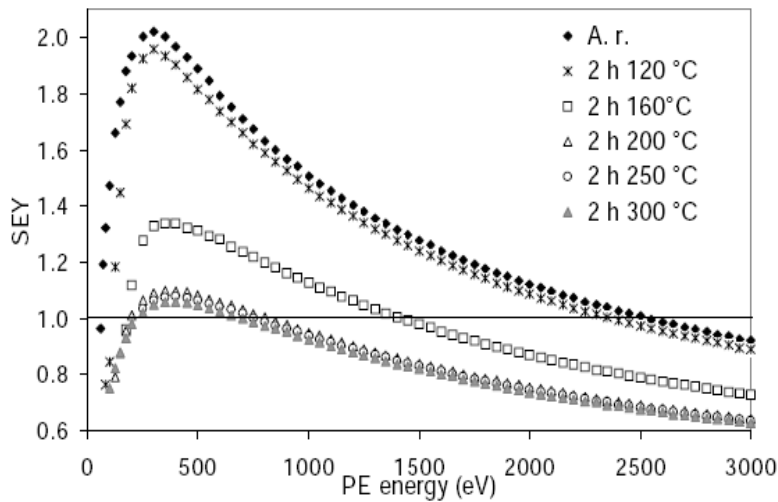
Cu surface : unbaked, baked, pure Cu



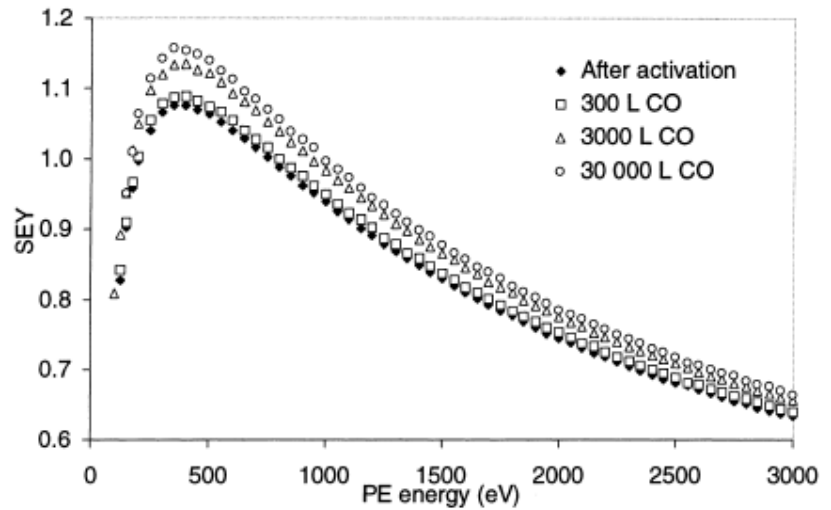
N. Hilleret *et al.*, LHC Project Report 433 2000, EPAC 00

- δ_{\max} :
 - ~ 2.3 in the **unbaked** case
 - ~ 1.8 with ***in-situ* bakeout** at 300 deg
 - 1.3 with ***in-situ* glow discharge** (value of pure Cu)

Activated NEG



C. Scheuerlein *et al.* Appl.Surf.Sci 172(2001)



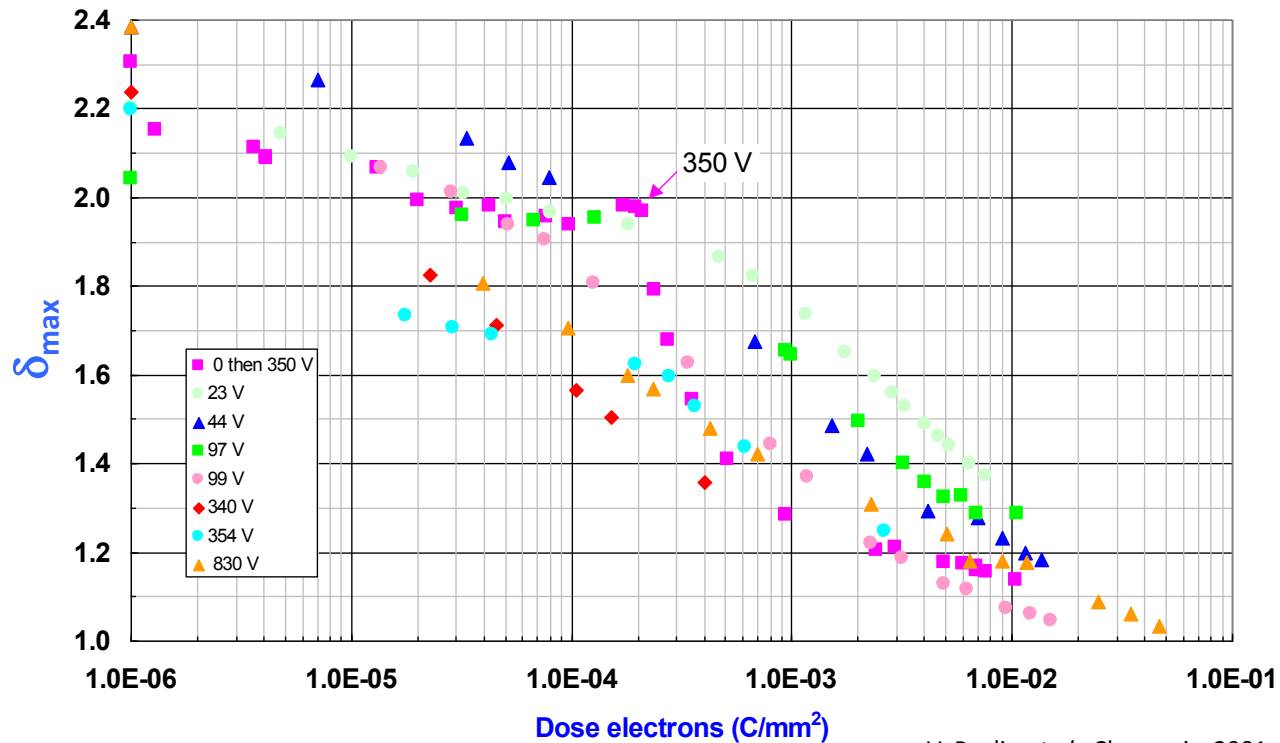
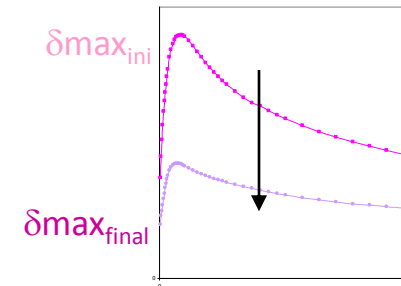
- Activated TiZrV film :
 - $\delta_{\max} \sim 1.1$

- Saturated TiZrV film :
 - $\delta_{\max} < 1.3$
 - H_2, H_2O, CO, CO_2
 - But $\delta_{\max} > 2$ when exposed to air !

Since δ_{\max} is very low, there are no multipacting in NEG vacuum chambers

LHC : scrubbing under electrons irradiation

- Reduction of SEY under electron irradiation
- 1 to 10 mC/mm² is required to have $\delta_{\max} < 1.3$
- Growth of a carbon layer (AES, XPS)

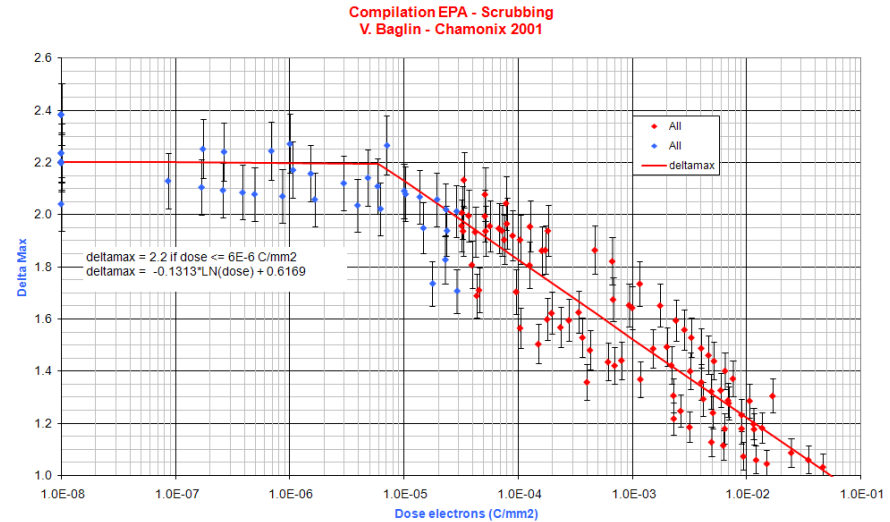


V. Baglin *et al.*, Chamonix, 2001

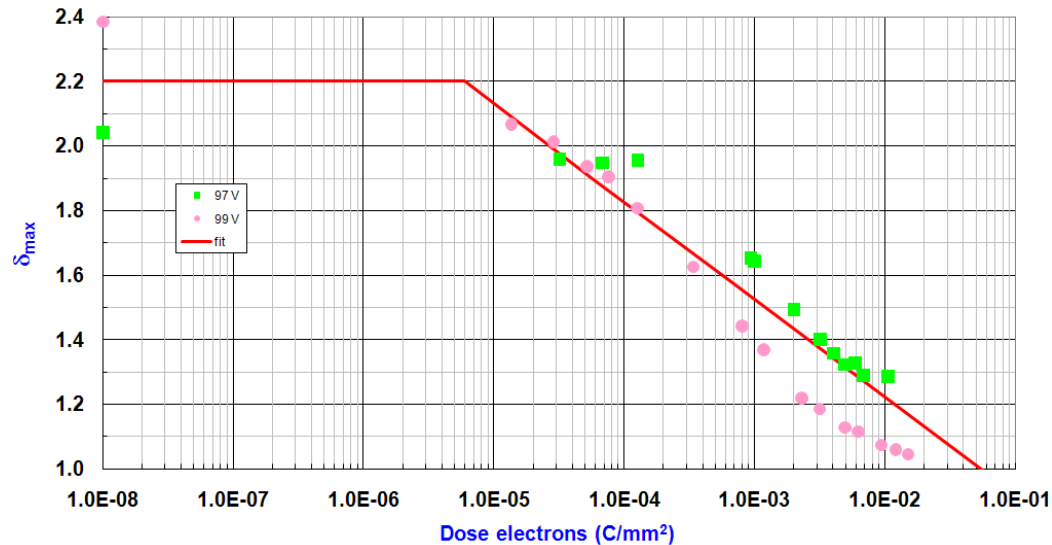
A very simple curve fit

- Fit well 100 eV curve

$$\begin{cases} \delta_{\max} = 2.2 \text{ if dose} \leq 6 \cdot 10^{-6} \text{ C/mm}^2 \\ \delta_{\max} = -0.1313 \ln(\text{dose}) + 0.6169 \end{cases}$$

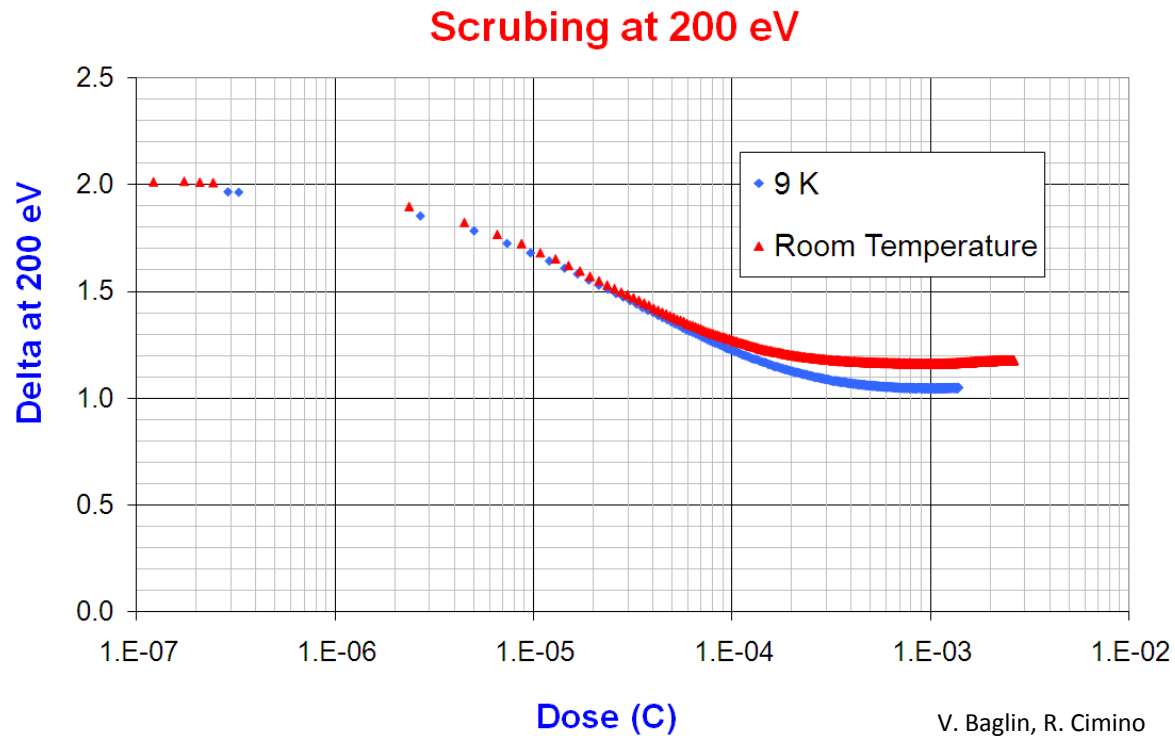
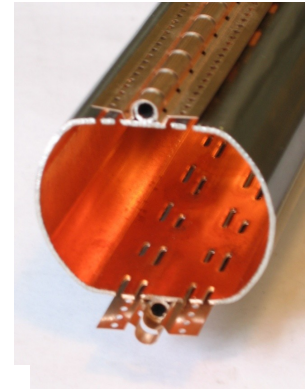


Compilation EPA - Scrubbing ~ 100 V
V. Baglin - Chamonix 2001

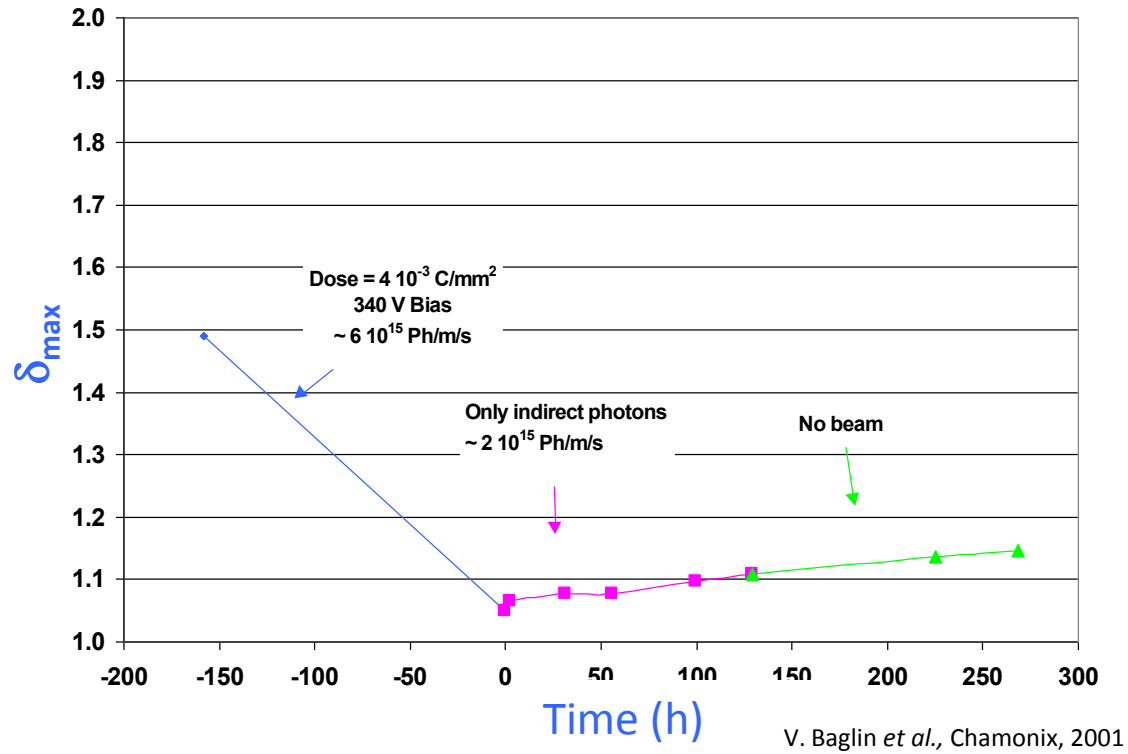


Scrubbing works also in cryogenic areas !!

- Unbaked by design
- Providing that the beam screen's surface coverage stays below a monolayer : cool down CB first
- **Scrubbing** at cryogenic temperature is **as much efficient as** at room temperature



After a stop : slight re-conditioning required

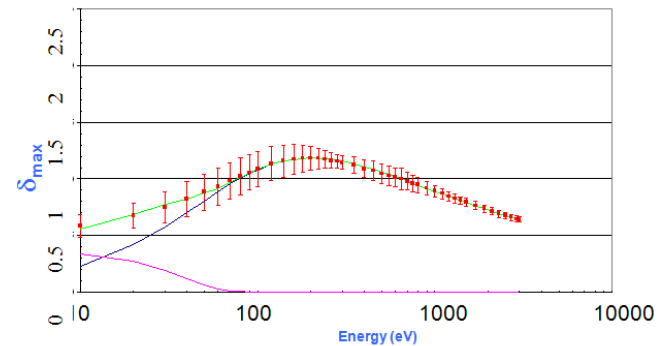
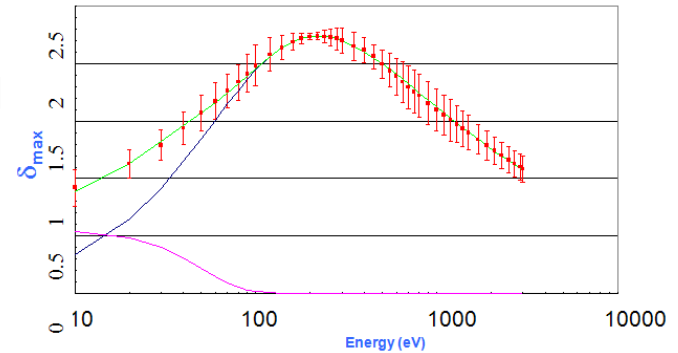


- Re-conditioning is necessary after a significant stop $\sim 0.1 / 10$ days for $P \sim 10^{-9}$ Torr
- Expected to be **much faster** than the initial conditioning (to be quantified)

What happen to the low energy electrons ?

- Detailed analysis of the SEY curves, revealed the presence of reflected electrons at low energy
- Low energy electrons are present in as received and scrubbed state
- The **reflected part** might be described by an exponential behaviour

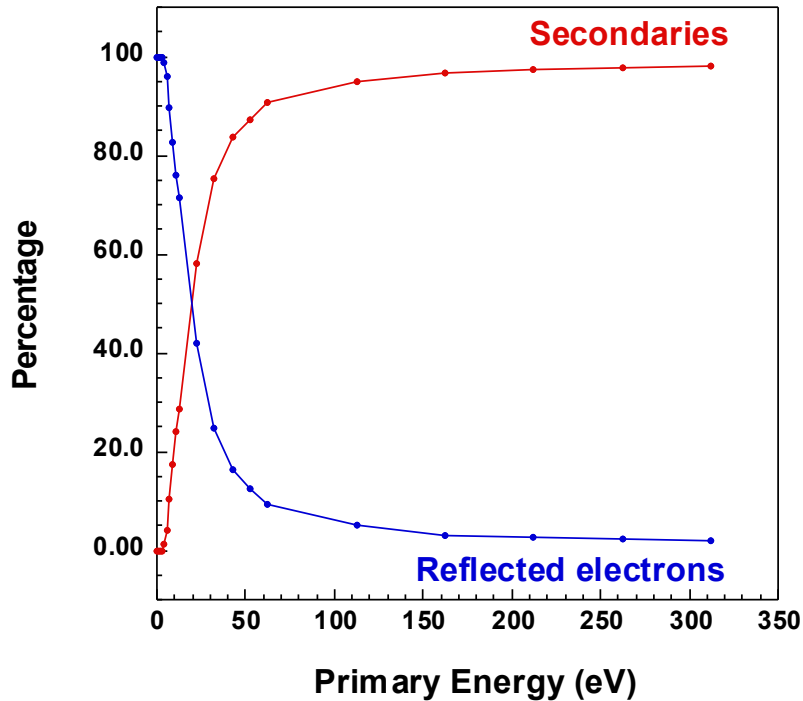
$$\delta(E) = \delta_{\max} \frac{s \frac{E}{E_{\max}}}{s-1 + \left(\frac{E}{E_{\max}}\right)^s} + a \exp\left(-\frac{E^2}{2\sigma^2}\right)$$



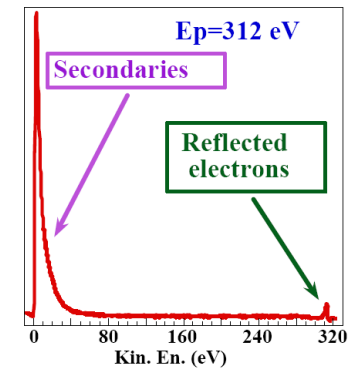
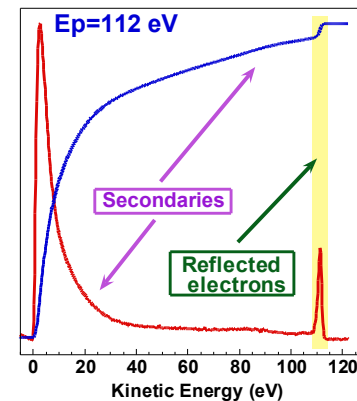
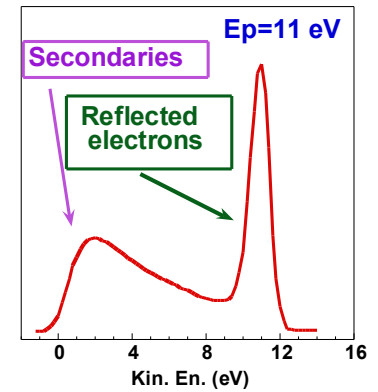
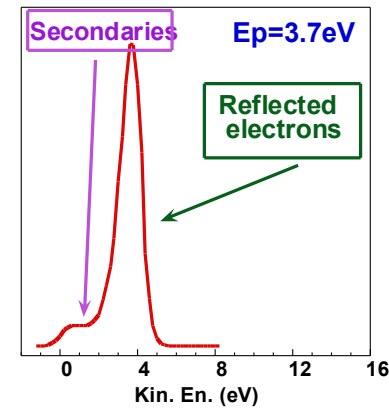
V. Baglin *et al.*, Chamonix, 2001

Electron reflectivity of Cu

- Measure of the EDC for several primary energies (E_p)
- Electrons with energy **below 20 eV have large reflectivity (> 50 %)**

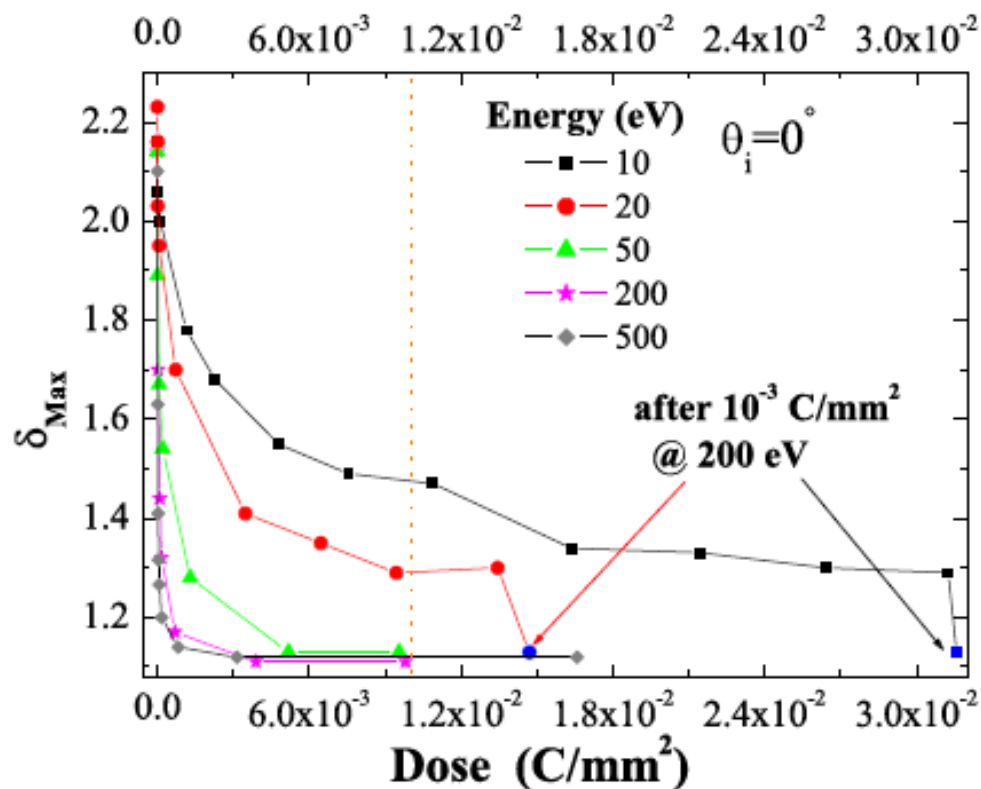


R. Cimino, I.R. Collins, App. Surf. Sci. 235, 231-235, (2004)



A consequence : impact on conditioning efficiency

- The conditioning rate is less efficient for electrons below 50 eV

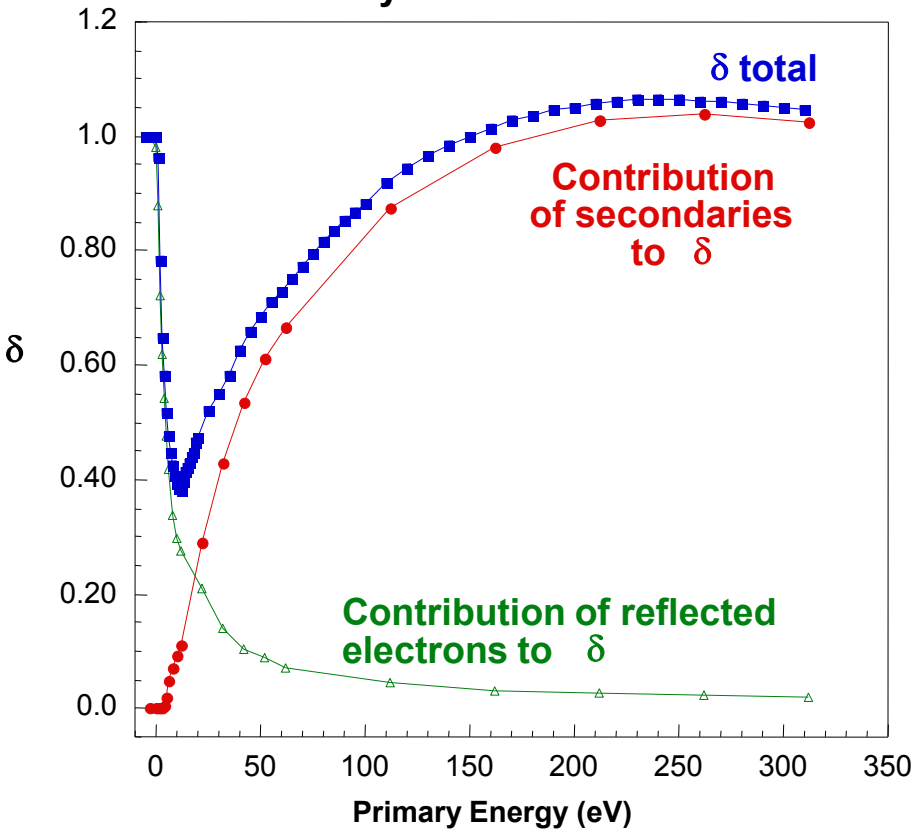


R. Cimino et. al. EPAC 2008, Genoa, Italy

SEY at cryogenic temperature

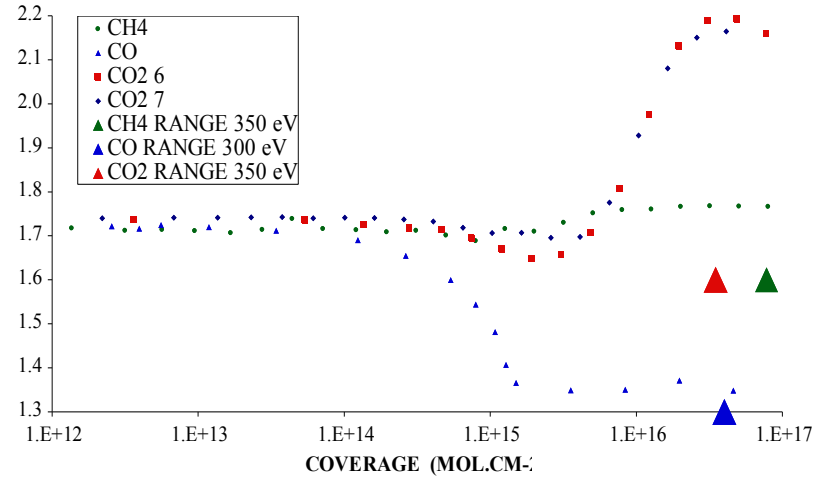
- Cu can be scrubbed **BUT**
- avoid gas condensation (H_2O , CO_2)

Fully scrubbed Cu



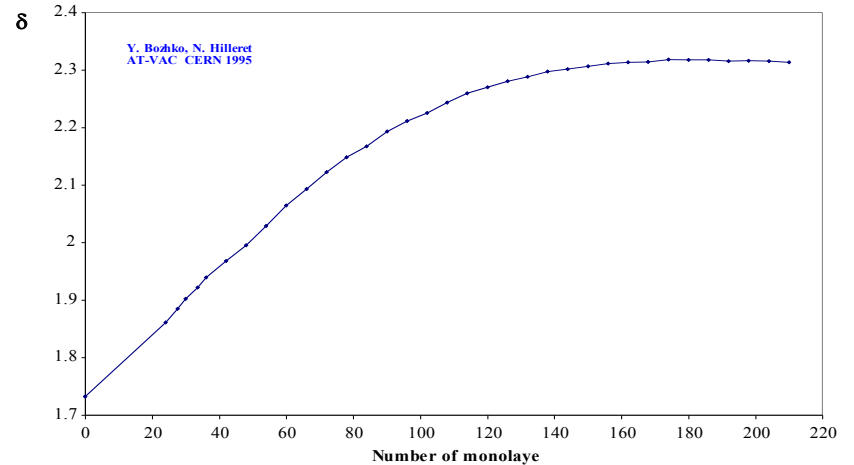
R. Cimino, I.R. Collins, App. Surf. Sci. 235, 231-235, (2004)

δ_{MAX} VERSUS COVERAGI



N. Hilleret. LHC MAC December 2004

Variation of maximum yield with amount of adsorbed

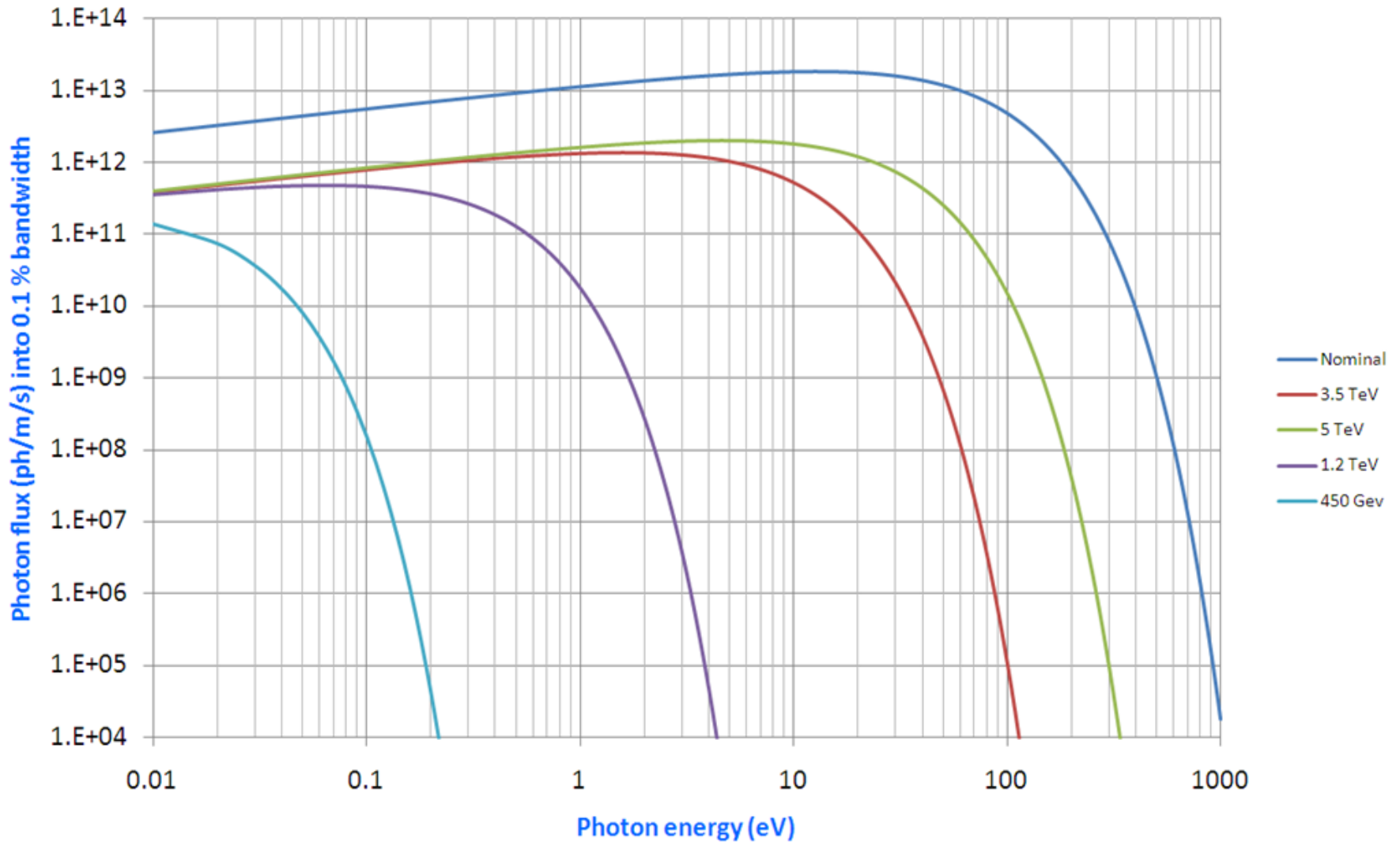


N. Hilleret *et. al.* Chamonix 2000

3. Photons related surface properties

LHC SR spectrum : UV

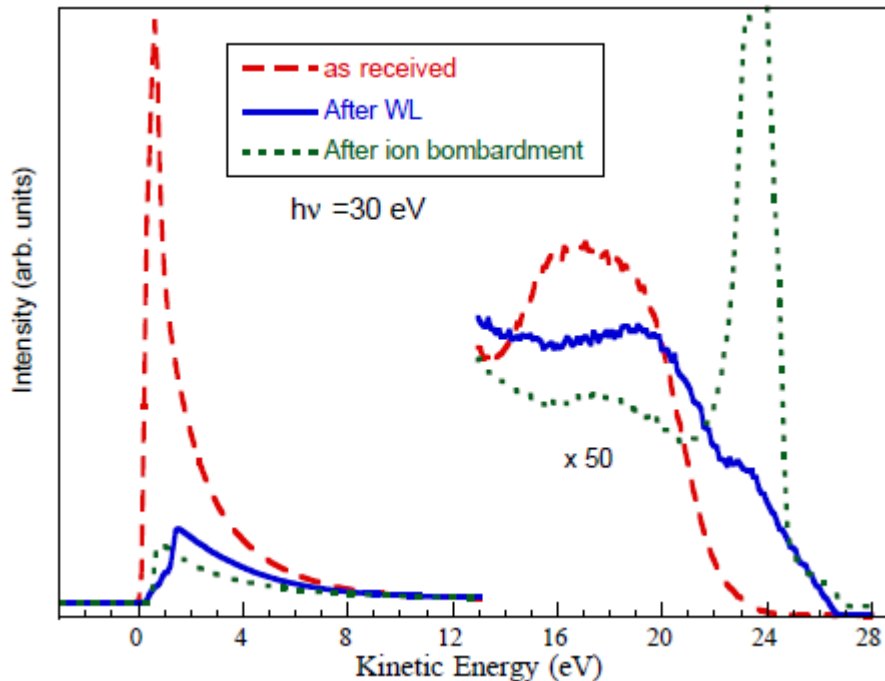
- With nominal parameters : 7 TeV and 585 mA
- With reduced beam current, 90 mA, and reduced beam energy



Energy of emitted photoelectrons

- Most of the photoelectrons have energies below 10 eV

Cu colaminated

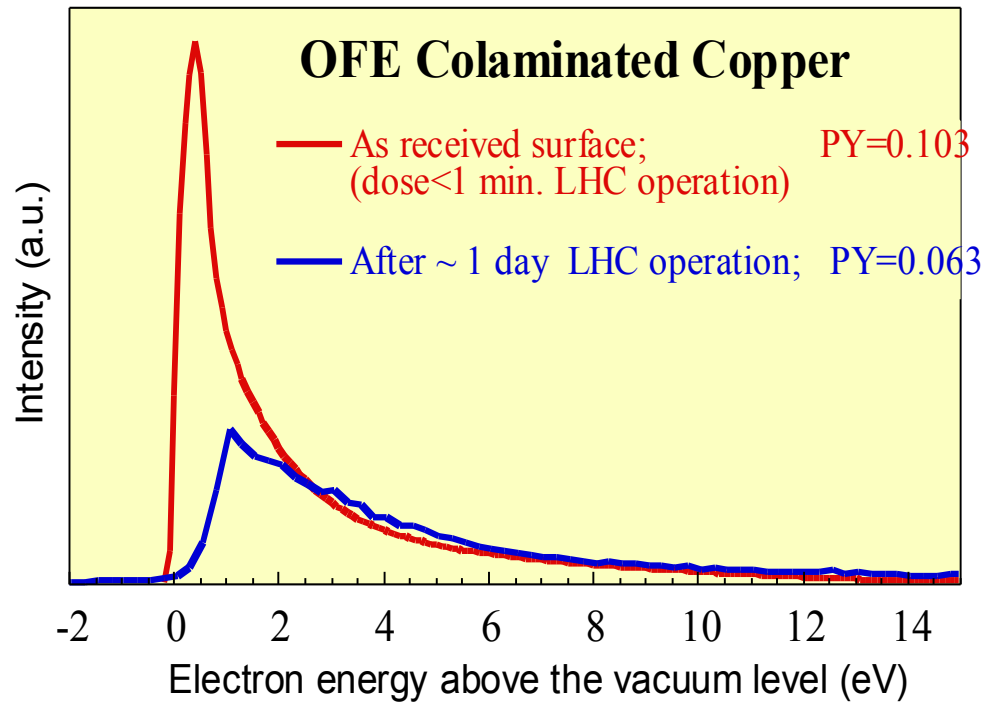


- A conditioning is observed under SR or glow discharge

R. Cimino *et al.* Phys. Rev. AB-ST 2 063201 (1999)

EDC under SR irradiation

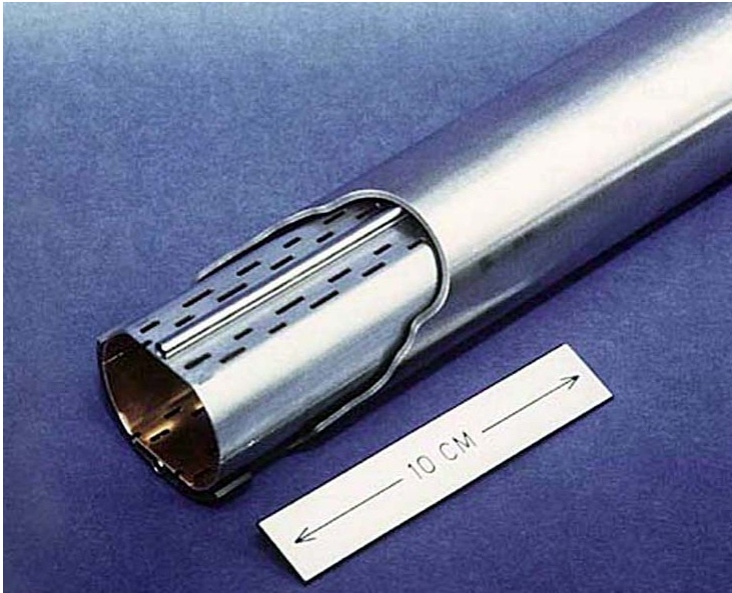
- SR irradiation **reduce** the amount of low energy photoelectrons
- The total yield is decreased by 40 % after 1 day of nominal LHC operation



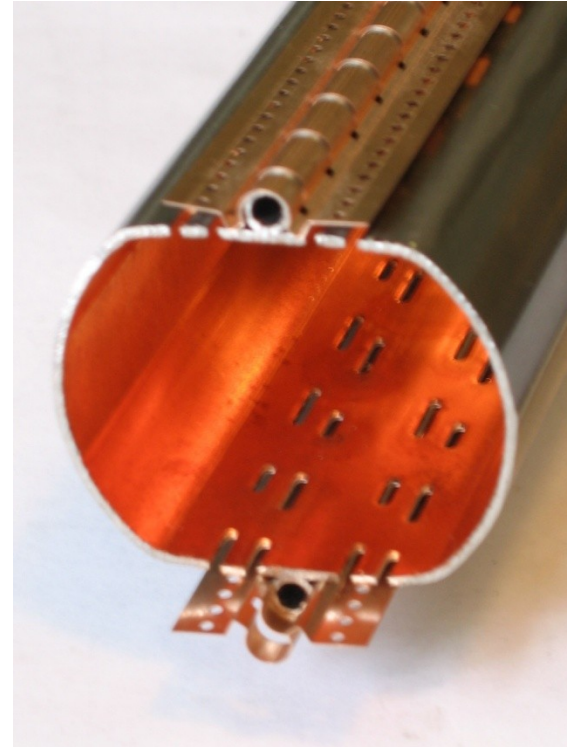
R. Cimino *et al.* Phys. Rev. AB-ST 2 063201 (1999)

LHC design

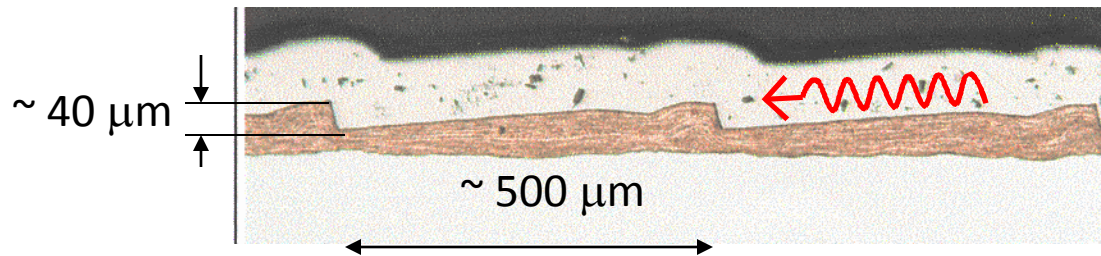
- **Sawteeth** are provided in the LHC beam screen to reduce the photoelectron yield and the forward reflectivity



Courtesy N. Kos CERN TE/VSC



Courtesy N. Kos CERN TE/VSC



Photon reflectivities of Cu materials

- Measured at ELLETRA with SR of 26 mrad grazing incidence (4.5 mrad in LHC)

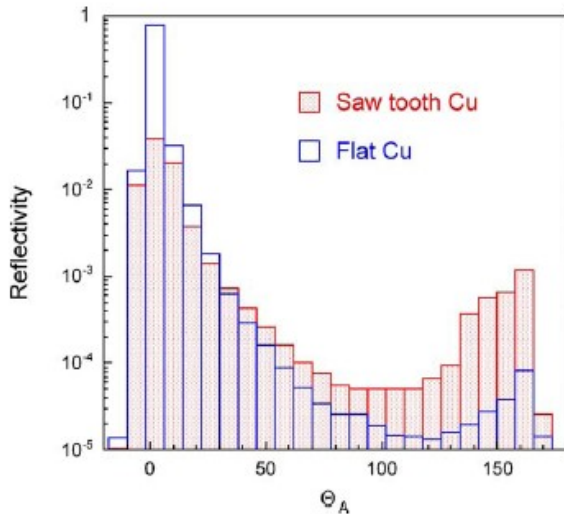


Fig. 2. Measured reflectivity, on the scattering plane, from a flat Cu sample (blue empty bars) and from the saw-tooth sample (red bars). Each point measure the reflectivity collected by the diode (whose angular dimension in the scattering plane was 8°).

- LHC sawtooth provides low :
 - forward reflection
 - back scattering
 - diffuse light

Table 1
Measured values of the forward scattering, back scattering and diffused light expressed in percentage of the incoming light

	Flat sample	Saw-tooth sample
Forward scattering (%)	80	4
Back scattering (%)	0	2
Diffused (%)	2	4
Total	82	10

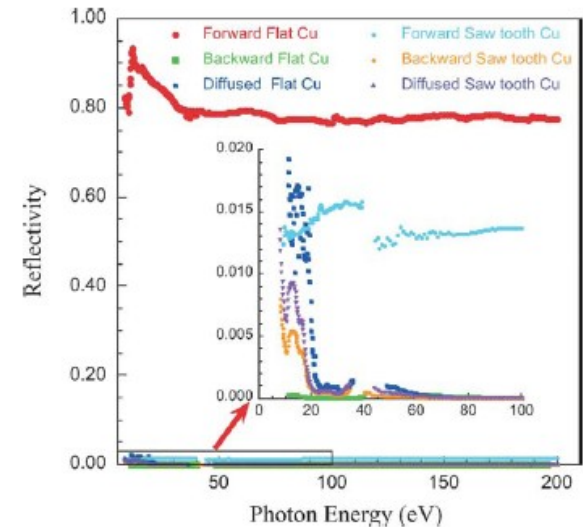
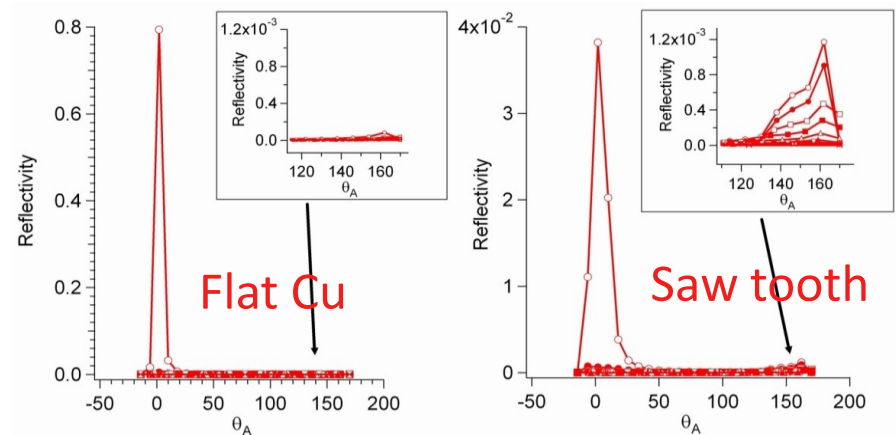


Fig. 3. Reflectivity of the measured flat and saw-tooth Cu surface vs. impinging monochromatic photon energy between 8 and 200 eV.

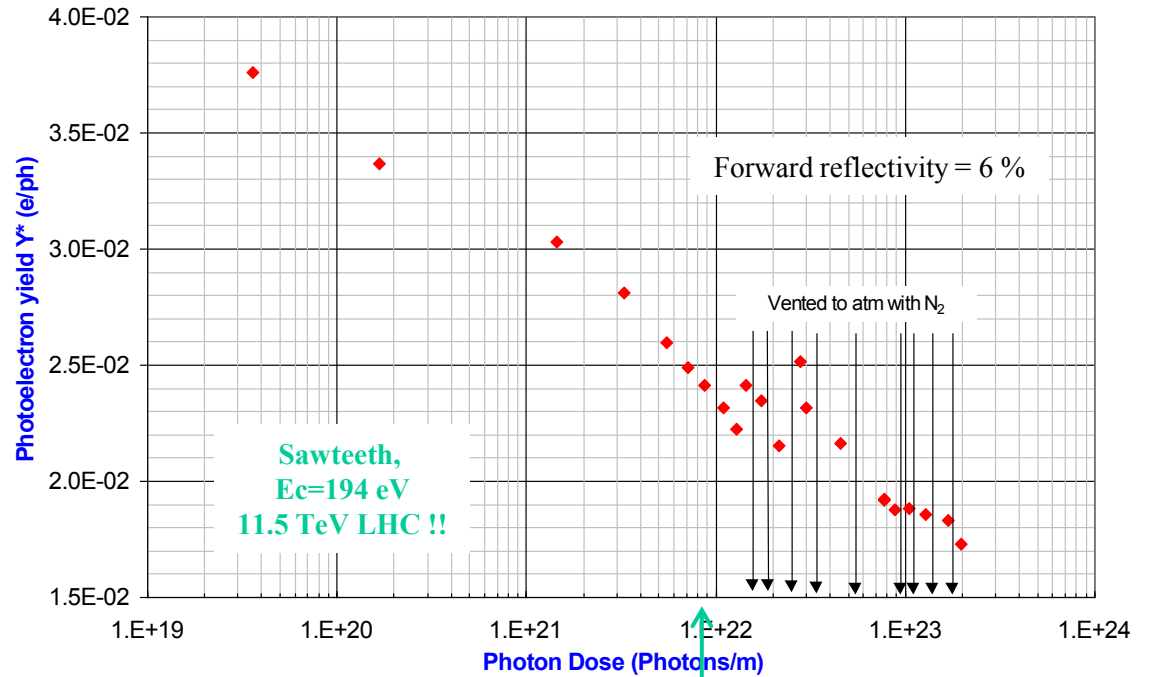


N. Mahne *et al.* App. Surf. Sci. 235, 221-226, (2004).

LHC Beam Screens

PEY, Reflectivity

- SR irradiation at EPA
- The photoyield decrease with **beam conditioning**
- It varies from 4 to 1 % under perpendicular incidence



V. Baglin *et al.*, CERN Chamonix XI, 2001

Behaviour with critical energy ?

- SR irradiation at EPA
- Grazing incidence, 11 mrad
- The photoyield **increases** when increasing critical energy.
- Photon reflectivity **slightly decreases** when increasing critical energy

Material	Status	45 eV		194 eV	
		R (%)	PY* (e/ph)	R (%)	PY* (e/ph)
Al	unbaked	-	0.11	-	0.32
Cu-smooth	unbaked	81	0.11	77	0.32
Cu-electrodeposited	unbaked	5	0.08	7	0.08
Cu-sawtooth	unbaked	8	0.03	7	0.04
TiZr	unbaked	20	0.06	17	0.08
TiZr	activated at 350°C	20	0.02	17	0.03

I.R. Collins *et al.* EPAC 1998, Stockholm, Sweden

NB : molecular desorption yields are linear in the range, 10 – 300 eV. So the photoelectron yield should be also proportional to critical energy

$$PY^* \sim E_c$$

Behaviour of technical materials under different treatments ?

- WL irradiation at BESSY
- Value ranges from 4 to 10 %
- Al exhibit the highest yield
- Colaminated Cu is 6 %

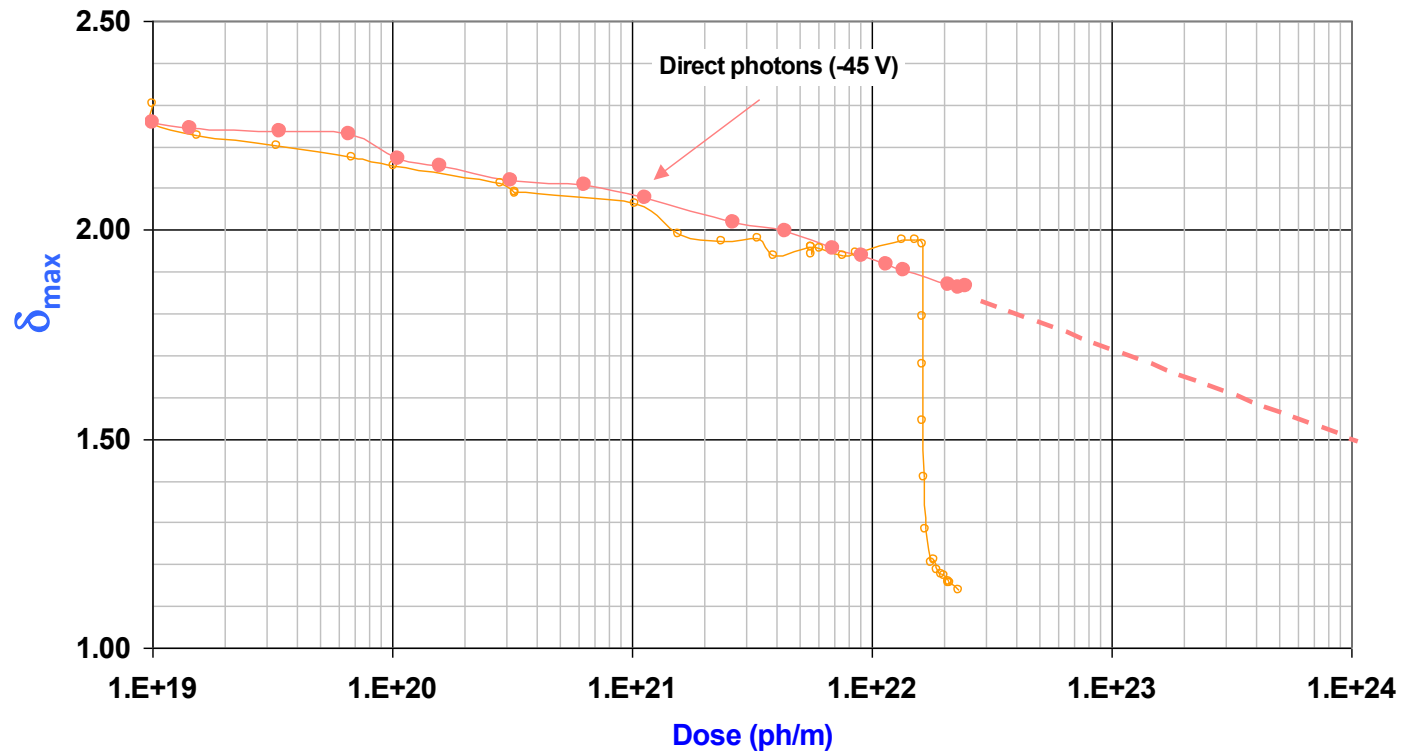
Sample	WL yield (electrons/photon)
Au	0.041 ± 0.002
Cu	0.063 ± 0.002
Cu-sp.	0.053 ± 0.002
Cu-ab.	0.093 ± 0.002
TiN	0.080 ± 0.002
TiN-sp.	0.120 ± 0.002
TiZr	0.088 ± 0.002
TiZr-ac.	0.055 ± 0.002
TiZr II	0.084 ± 0.002
TiZr II ac.	0.057 ± 0.002
Cu-el.	0.070 ± 0.002
Cu-el.-an.	0.062 ± 0.002
Pd	0.072 ± 0.002
Pd-an.	0.080 ± 0.002
St 707	0.053 ± 0.002
St 707-ac.	0.035 ± 0.002
Al	0.106 ± 0.002
Al-sp.	0.835 ± 0.002

R. Cimino *et al.* Phys. Rev. AB-ST 2 063201 (1999)

Photon scrubbing vs photon dose

- A **minor reduction** of the SEY due to SR can be observed
- Cannot rely on SR to scrub the LHC

SEY vs dose photon, EPA #12, Ech A -45V, direct, 194 eV
chambre dents de scie



1 year of nominal
LHC operation
yields to ~ 1.5

Thank you for your attention !!!